Notice of References Cited

Application/Control No. 10/085,367	Applicant(s)/Patent Under Reexamination JEUNG ET AL.		
Examiner	Art Unit		
Viet Q Nguyen	2818	Page 1 of 1	

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	Α	US-2002/0179999	12-2002	Lee et al.	257/530
*	В	US-6,214,669	04-2001	Hisamune, Yosiaki	438/259
*	U	US-6,204,541	03-2001	Togami et al.	257/390
*	۵	US-6,674,661	01-2004	Becker, Scott T.	365/104
*	E	US-6,531,393	03-2003	Huang et al.	438/655
*	F	US-6,653,685	11-2003	Katayama et al.	257/324
*	G	US-6,633,496	10-2003	Maayan et al.	365/63
*	Н	US-6,570,810	05-2003	Wong, Sau Ching	365/230.03
*	ı	US-6,459,119	10-2002	Huang et al.	257/314
*	J	US-6,084,794	07-2000	Lu et al.	365/104
*	К	US-5,862,076	01-1999	Eitan, Boaz	365/185.16
	L	US-			
	М	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	S					
	Т					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
		Viet Q. Nguyen Primary Examinar
	V	PARISH ETTIMA
	w	
	X	
	^	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.